

## 32 BIT/DUAL 16 BIT BINARY UP COUNTER WITH BYTE MULTIPLEXED THREE-STATE OUTPUTS

July 1998

### FEATURES:

- DC to 15 MHz Count Frequency
- Byte Multiplexer
- DC to 1 MHz Scan Frequency
- +4.75V to +5.25V Operation ( $V_{DD}-V_{SS}$ )
- Three-State Data Outputs, Bus and TTL Compatible
- Inputs TTL and CMOS Compatible
- Unique Cascade Feature Allows Multiplexing of Successive Bytes of Data in Sequence in Multiple Counter Systems
- Low Power Dissipation
- LS7060, LS7062 (DIP); LS7060-S, LS7062-S (SOIC)  
See Figures 1 and 2

### DESCRIPTION:

The LS7060/LS7062 is a monolithic, ion implanted MOS Silicon Gate, 32 bit/dual 16 bit up counter. The IC includes latches, multiplexer, eight three-state binary data output drivers and output cascading logic.

### DESCRIPTION OF OPERATION:

#### 32 (16) BIT BINARY UP COUNTER - LS7060 (LS7062)

The 32(16) bit static ripple through counter increments on the negative edge of the input count pulse. Maximum ripple time is 4 $\mu$ s (2 $\mu$ s) - transition count of 32(16) ones to 32(16) zeros. Guaranteed count frequency is DC to 15MHz. See Figure 9A(9B) for Block Diagram.

#### $\overline{\text{COUNT}}$ , $\overline{\text{ALT COUNT}}$ (LS7060)

Input count pulses to the 32 bit counter may be applied through either of these two inputs. The  $\overline{\text{ALT COUNT}}$  input circuitry contains a Schmitt trigger network which allows proper counting with "infinitely" long clock edges. A high applied to either of these two inputs inhibits counting.

#### $\overline{\text{COUNT A}}$ , $\overline{\text{ALT COUNT A}}$ (LS7062)

Input count pulses to the first 16 bit counter may be applied through either of these two inputs. The  $\overline{\text{ALT COUNT A}}$  input circuitry contains a Schmitt trigger network which allows proper counting with "infinitely" long clock edges. A high applied to either of these two inputs inhibits counting.

#### $\overline{\text{RESET}}$

All 32 counter bits are reset to zero when  $\overline{\text{RESET}}$  is brought low for a minimum of 1 $\mu$ s.  $\overline{\text{RESET}}$  must be high for a minimum of 300ns before next valid count can be recorded.

#### $\overline{\text{TEST COUNT}}$ (LS7060)

Count pulses may be applied to the last 16 bits of the binary counter through this input, as long as Bit 16 of the counter is a low. The counter advances on the negative transition of these pulses. This input is intended to be used for test purposes.

PIN ASSIGNMENT - TOP VIEW

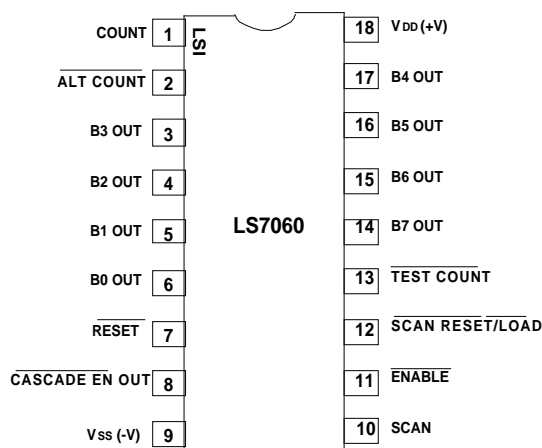


FIGURE 1

PIN ASSIGNMENT - TOP VIEW

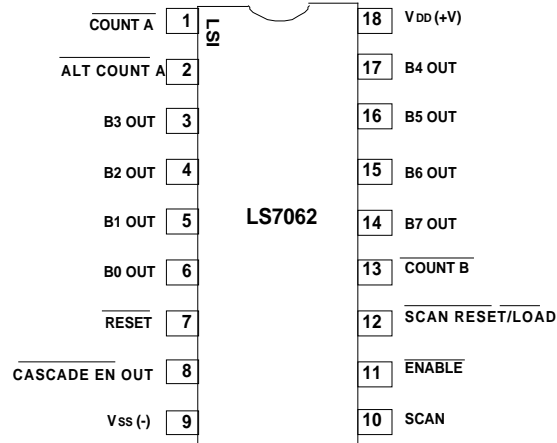


FIGURE 2

#### $\overline{\text{COUNT B}}$ (LS7062)

Count pulses may be applied to the last 16 bits of the binary counter through this input. The counter advances on the negative transition of these pulses.

#### LATCHES - LS7060 (LS7062)

32 bits of latch are provided for storage of counter data. All latches are loaded when the  $\overline{\text{LOAD}}$  input is brought low for a minimum of 1 $\mu$ s and kept low until a minimum of 4 $\mu$ s (2 $\mu$ s) has elapsed from previous negative edge of count pulse (ripple time). Storage of valid data occurs when  $\overline{\text{LOAD}}$  is brought high for a minimum of 250ns before next negative edge of count pulse or  $\overline{\text{RESET}}$ .

## SCAN COUNTER AND DECODER

The scan counter is reset to the least significant byte position (State 1) when  $\overline{\text{SCAN RESET}}$  input is brought low for a minimum of  $1\mu\text{s}$ . The scan counter is enabled for counting as long as the  $\overline{\text{ENABLE}}$  input is held low. The counter advances to the next significant byte position on each negative transition of the SCAN pulse. When the scan counter advances to State 5 it disables the Output Drivers and stops in that state until  $\overline{\text{SCAN RESET}}$  is again brought low.

## SCAN

When the scan counter is enabled, each negative transition of this input advances the scan counter to its next state. When SCAN is low the Data Outputs are disabled. When SCAN is brought high the Data Outputs are enabled and present the latched counter data corresponding to the present state of the scan counter. Therefore, in microprocessor applications, the Data Output Bus may be utilized for other activities while new data is propagating to the outputs. This positive SCAN pulse can be viewed as a "Place the next byte on my bus" instruction from the microprocessor. Minimum positive and negative pulse widths of 500ns for the SCAN signal are required for scan counter operation.

## SCAN RESET/LOAD

When this input is brought low for a minimum of  $1\mu\text{s}$ , the scan counter is reset to State 1, the least significant byte position, and the latches are simultaneously loaded with new count information.

## ENABLE

When this input is high, the scan counter and the Data Outputs are disabled. When  $\overline{\text{ENABLE}}$  is low, the scan counter and Data Outputs are enabled for normal operation. Transition of this input should only be made while the SCAN input is in a low state in order to prevent false clocking of the scan counter.

## CASCADE ENABLE

This output is normally high. It transitions low and stays low when the scan counter advances to State 5. In a multiple counter system this output is connected to the  $\overline{\text{ENABLE}}$  input of the next counter in the cascade string. The SCAN input and  $\overline{\text{SCAN RESET/LOAD}}$  input are carried to all the counters in the "Cascade". Counter 1 then presents its bytes of data to the Output Bus on each positive transition of the SCAN pulse as previously discussed. When State 5 of Counter 1 is achieved, Counter 2 presents its data to the Output Bus. This sequence continues until all counters in the cascade have been addressed. See Figure 5 for an illustration of a 3 device cascade design. This output is TTL and CMOS compatible.

## THREE-STATE DATA OUTPUT DRIVERS

The eight Data Output Drivers are disabled when either  $\overline{\text{ENABLE}}$  input is high, the scan counter is in State 5, or the SCAN input is low. The Output Drivers are TTL and Bus compatible.

The information included herein is believed to be accurate and reliable. However, LSI Computer Systems, Inc. assumes no responsibilities for inaccuracies, nor for any infringements of patent rights of others which may result from its use.

## ABSOLUTE MAXIMUM RATINGS:

PARAMETER	SYMBOL	VALUE	UNIT
Storage Temperature	T <sub>STG</sub>	-55 to +150	°C
Operating Temperature	T <sub>A</sub>	0 to +70	°C
Voltage (any pin to V <sub>SS</sub> )	V <sub>IN</sub>	+10 to -0.3	V

## DC ELECTRICAL CHARACTERISTICS:

(V<sub>DD</sub> = +5V ± 5%, V<sub>SS</sub> = 0V, T<sub>A</sub> = 0°C to +70°C unless otherwise noted.)

PARAMETER	SYMBOL	Min	MAX	UNIT	CONDITIONS
Power Supply Current	I <sub>DD</sub>	-	15	mA	At Maximum Operating Frequency V <sub>DD</sub> = Max, Outputs No Load
Input High Voltage	V <sub>IH</sub>	+3.5	V <sub>DD</sub>	V	-
Input Low Voltage	V <sub>IL</sub>	0	+0.6	V	-
Output High Voltage					
CASCADE ENABLE	V <sub>OH</sub>	V <sub>DD</sub> -0.2	-	V	I <sub>O</sub> = 0, V <sub>DD</sub> = Min
B0 - B7		+2.4	-	V	I <sub>O</sub> = -100μA, V <sub>DD</sub> = Min
Output Low Voltage		+2.4	-	V	I <sub>O</sub> = -260μA, V <sub>DD</sub> = Min
CASCADE ENABLE	V <sub>OL</sub>	-	+0.2	V	I <sub>O</sub> = 750μA, V <sub>DD</sub> = Min
B0 - B7			+0.4	V	I <sub>O</sub> = 0, V <sub>DD</sub> = Min
Output Source Current	I <sub>source</sub>	3.0	-	mA	I <sub>O</sub> = 1.6mA, V <sub>DD</sub> = Min
B0 - B7 Outputs		4.8	-	mA	V <sub>O</sub> = +1.2V, V <sub>DD</sub> = Min
		7.3	-	mA	V <sub>O</sub> = +0.8V, V <sub>DD</sub> = Min
Output Sink Current	I <sub>sink</sub>	5.7	-	mA	V <sub>O</sub> = +0.4V, V <sub>DD</sub> = Min
B0 - B7 Outputs		4.0	-	mA	V <sub>O</sub> = +1.2V, V <sub>DD</sub> = Min
		2.2	-	mA	V <sub>O</sub> = +0.8V, V <sub>DD</sub> = Min
Output Leakage Current	I <sub>OL</sub>	-	1	μA	V <sub>O</sub> = +0.4V, V <sub>DD</sub> = Min
B0 - B7 (Off State)					
Input Capacitance	C <sub>IN</sub>	-	6	pF	T <sub>A</sub> = 25°C, f = 1MHz
Output Capacitance	C <sub>OUT</sub>	-	12	pF	T <sub>A</sub> = 25°C, f = 1MHz
Input Leakage Current	I <sub>LI</sub>	-	1	μA	V <sub>DD</sub> = Max
ENABLE, RESET, SCAN					

**INPUT CURRENT**

*SCAN RESET/LOAD	I <sub>IH</sub>	-	-2.5	μA	V <sub>DD</sub> = Max, V <sub>IH</sub> = +3.5
	I <sub>IL</sub>	-	-5	μA	V <sub>DD</sub> = Max, V <sub>IL</sub> = 0
**All Count inputs	I <sub>IH</sub>	-	5	μA	V <sub>DD</sub> = Max, V <sub>IH</sub> = +3.5
	I <sub>IL</sub>	-	1	μA	V <sub>DD</sub> = Max, V <sub>IL</sub> = 0

\*Input has internal pull-up resistor to V<sub>DD</sub>

\*\* Inputs have internal pull-down resistor to V<sub>SS</sub>

**DYNAMIC ELECTRICAL CHARACTERISTICS:**

(V<sub>DD</sub> = +5V ± 5%, V<sub>SS</sub> = 0V, T<sub>A</sub> = 0°C to +70°C unless otherwise noted.)

PARAMETER	SYMBOL	MIN	MAX	UNIT	CONDITIONS
Count Frequency (All Count inputs)	fc	DC	15	MHz	-
Count Pulse Width (All Count Inputs)	tCPW	30	-	ns	Measured at 50% point, Max tr, tf = 10ns
Count Rise & Fall time (Pins 1, 13)	tr, tf	-	30	μs	-
Count Ripple Time (Pins 1, 2 - LS7062)	tCR	-	4	μs	Transition from 32 ones to 32 zeros from negative edge of count pulse
Count Ripple Time (Pin 13 - LS7060)	tCR	-	2	μs	Transition of 16 bits from all ones to all zeros from negative edge of count pulse
Reset Pulse Width (All Counter Stages Fully Reset)	trPW	500	-	ns	Measured at 50% point Max tr, tf = 200ns
RESET Removal Time (Reset Removed From All Counter Stages)	tRR	-	250	ns	Measured from $\overline{\text{RESET}}$ signal at V <sub>IH</sub>
SCAN Frequency	fsc	-	1	MHz	
SCAN Pulse Width	tSCPW	500	-	ns	Measured at 50% point Max tr, tf = 100ns
SCAN RESET/LOAD Pulse Width (All latches loaded and Scan Counter Reset to Least Significant Byte)	trSCPW	1	-	μs	Measured at 50% point Max tr, tf = 200ns
SCAN RESET/LOAD Removal Time (Reset Removed from Scan Counter; Load Command Removed From Latches)	trSCR	-	250	ns	Measured from $\overline{\text{SCAN RESET/LOAD}}$ at V <sub>IH</sub>
Output Disable Delay Time (B0 - B7)	tDOD	-	200	ns	Transition to Output High Impedance State Measured From Scan at V <sub>IL</sub> or ENABLE at V <sub>IH</sub>
Output ENABLE Delay Time (B0 - B7)	tDOE	-	200	ns	Transition to Valid On State Measured from Scan at V <sub>IH</sub> and ENABLE at V <sub>IL</sub> ; Delay to Valid Data Levels for C <sub>OL</sub> = 10pF and one TTL Load or Valid Data Currents for High Capacitance Loads
Output Delay Time CASCADE ENABLE	tDCE	-	300	ns	Negative Transition from Scan at V <sub>IL</sub> and ST5 of Scan Counter or Positive Transition From $\overline{\text{SCAN RESET/LOAD}}$ at V <sub>IL</sub> to Valid Data Levels for C <sub>OL</sub> = 10pF and one TTL Load

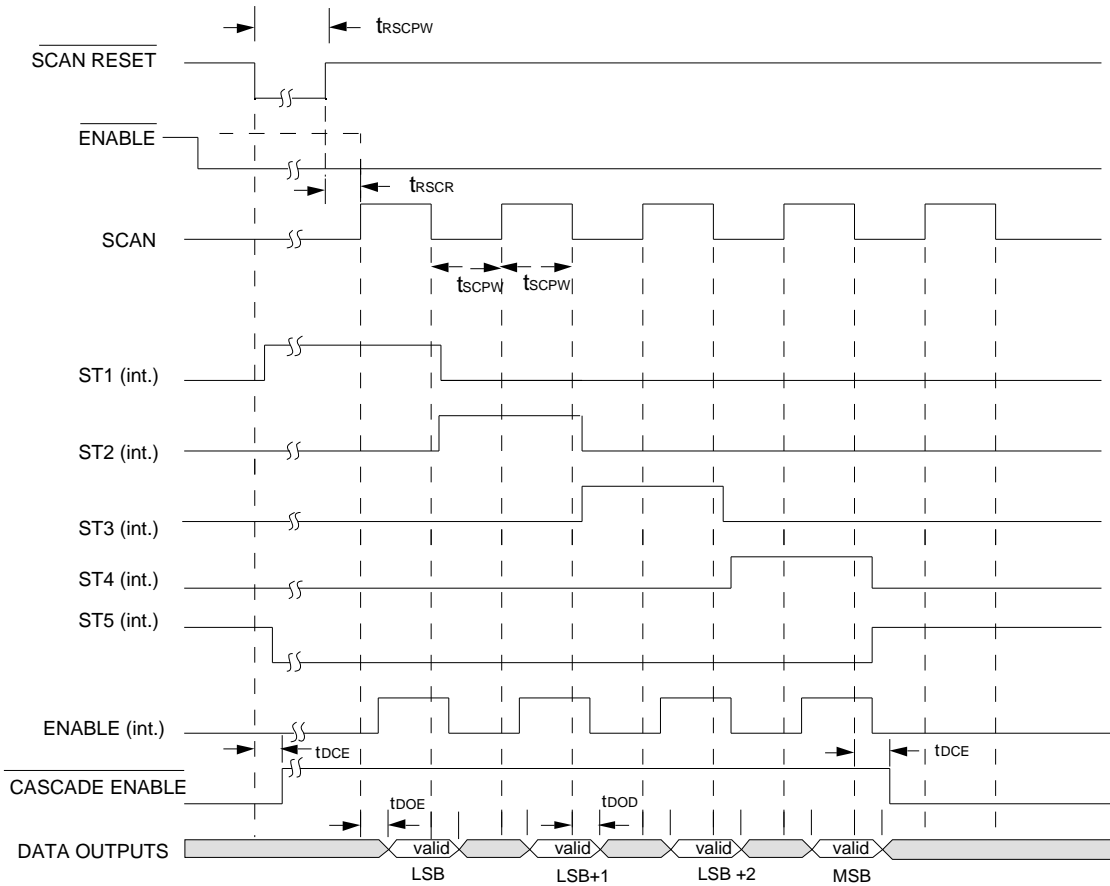


FIGURE 3. SCAN COUNTER & DECODER OUTPUTS TIMING DIAGRAM

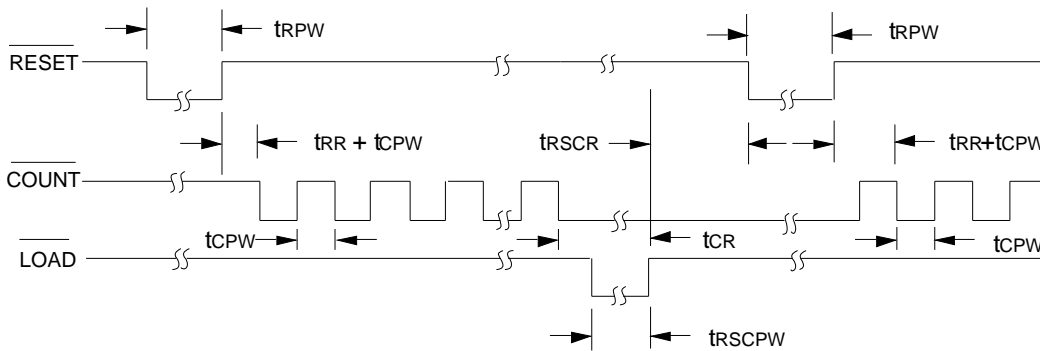


FIGURE 4. COUNTER TIMING DIAGRAM

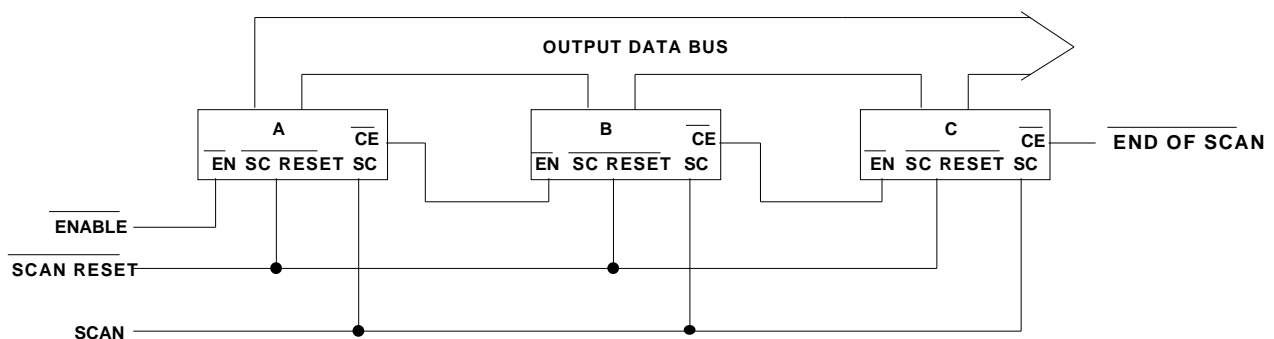


FIGURE 5. ILLUSTRATION OF A 3 DEVICE CASCADE

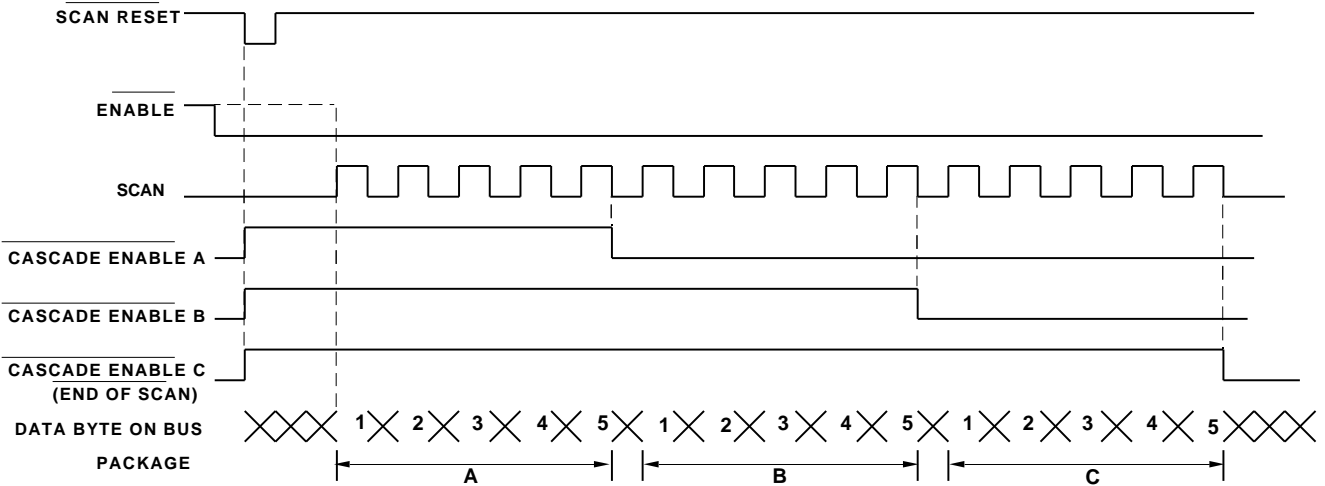


FIGURE 6. TIMING DIAGRAM FOR THE 3 DRIVER CASCADE

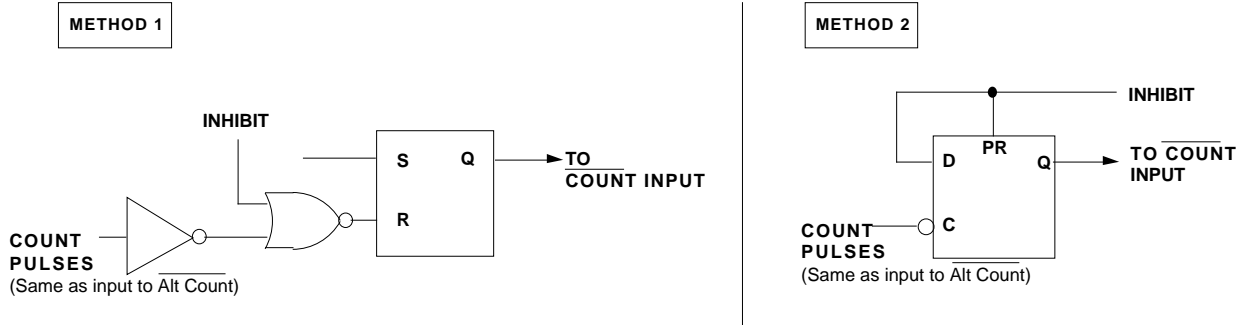
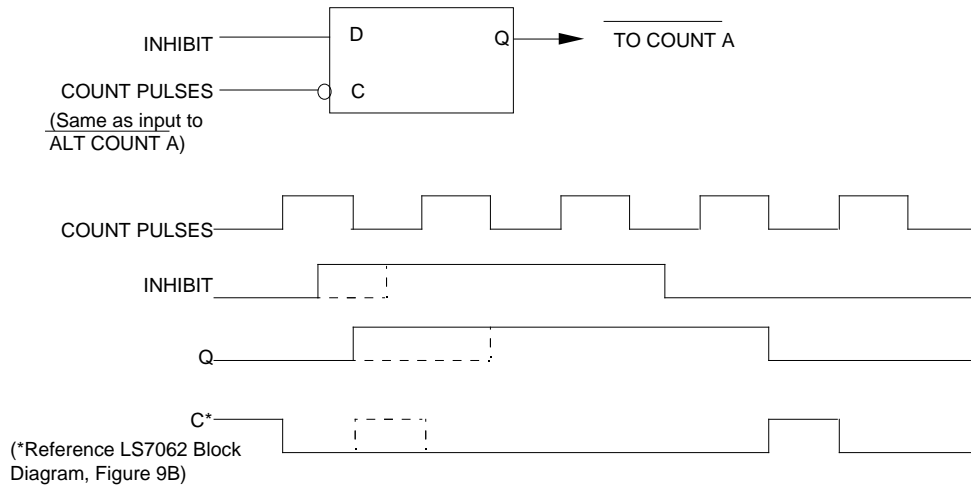


FIGURE 7. SYNCHRONIZING INHIBIT WITH COUNT PULSES FOR LS7060



NOTE: Count A may only change during positive portion of Count Pulses (Alt Count A) when Count A is used as an inhibit.

FIGURE 8. SYNCHRONIZING INHIBIT WITH COUNT PULSES FOR COUNTER A FOR LS7062

FIGURE 9A. LS7060 BLOCK DIAGRAM

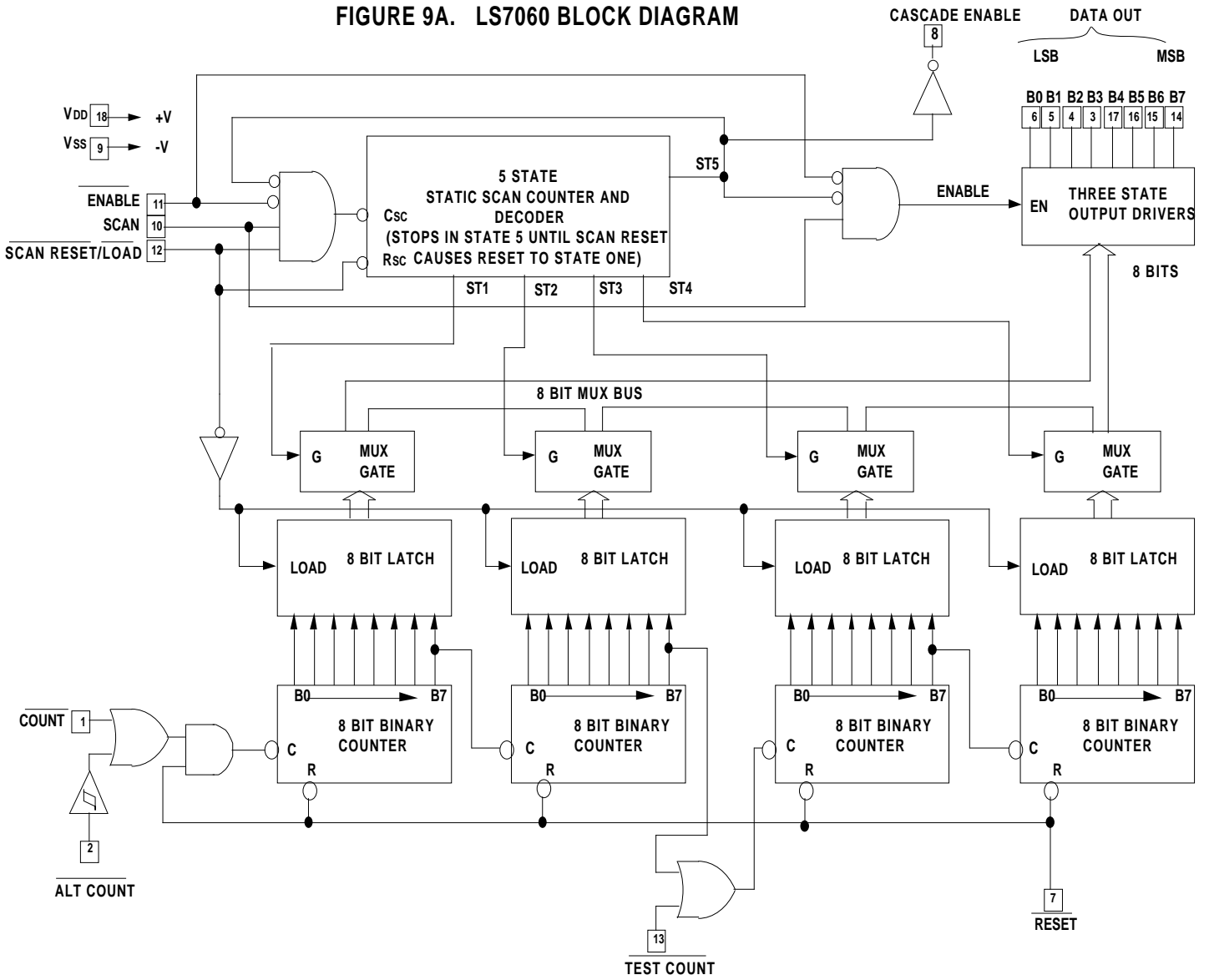


FIGURE 9B. LS7062 BLOCK DIAGRAM

